

FCC RF Test Report

Product Name: Smart Phone

Product Model: HUAWEI D2-6114, D2-6114, HW-03E

Report Number: SYBH(Z-RF)014012013-2002

FCC ID: QISD2-6114

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Notice

1. The laboratory has Passed the accreditation by China National Accreditation Service for Conformity Assessment (CNAS). The accreditation number is L0310.
2. The laboratory has Passed the accreditation by The American Association for Laboratory Accreditation (A2LA). The accreditation number is 2174.01.
3. The laboratory has been listed by the US Federal Communications Commission to perform electromagnetic emission measurements. The site recognition number is 97456.
4. The laboratory has been listed by Industry Canada to perform electromagnetic emission measurements. The recognition numbers of test site are 6369A-2.
5. The laboratory has been listed by the VCCI to perform EMC measurements. The accreditation numbers of test site No.1 are R-2364, G-415, C-2583, and T-256, and the accreditation numbers of test site No.2 are R-3760, G-485, C-4210 and T-1237.
6. The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
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9. Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



Modification Record

No.	Last Report No.	Modification Description
1		First report.



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1 General Information

1.1 Applied Standard

Applied Rules:	47 CFR FCC Part 2, Subpart J (2012-10-01 Edition) 47 CFR FCC Part 15, Subpart C (2012-10-01 Edition)
Test Method:	FCC PUBLIC NOTICE DA 00-705 Filing and Measurement Guidelines for Frequency Hopping Spread Spectrum Systems (Released March 30, 2000) ANSI C63.4-2003/-2009, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz. ANSI C63.10-2009, American National Standard for Testing Unlicensed Wireless Devices.

1.2 Test Location

Test Location 1:	Reliability Laboratory of Huawei Technologies Co., Ltd.
Address:	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C

1.3 Test Environment Condition

Ambient Temperature:	19.5 to 25 °C
Ambient Relative Humidity:	45 to 55 %
Atmospheric Pressure:	Not applicable



2 Test Summary

Test Item	FCC Part No.	Requirements	Test Result	Verdict (NOTE)
20dB Emission Bandwidth (EBW)	15.247(a)(1)	No limit.	Appendix A	Pass
Carrier Frequency Separation	15.247(a)(1)	$\geq \text{MAX} \{25\text{kHz}, \text{IIF}\{\text{output power} \leq 125\text{mW}, 2/3 * 20\text{dB EBW}, 20\text{dB EBW}\}\}$.	Appendix B	Pass
Number of Hopping Channel	15.247(a)(1)(iii)	≥ 15 channels.	Appendix C	Pass
Time of Occupancy (Dwell Time)	15.247(a)(1)(iii)	$< 0.4\text{s}$ within a period of $(0.4\text{s} * \text{hopping number})$.	Appendix D	Pass
Maximum Peak Conducted Output Power	15.247(b)(1)	$< 1\text{ W}$ if using ≥ 75 non-overlapping channels.	Appendix E	Pass
Band edge spurious emission	15.247(d)	$< -20\text{ dBc}/100\text{ kHz}$ if total peak power \leq power limit.	Appendix F	Pass
Conducted RF Spurious Emission	15.247(d)	$< -20\text{ dBc}/100\text{ kHz}$ if total peak power \leq power limit.	Appendix G	Pass
Radiated Emissions in the Restricted Bands	15.247(d) 15.209	FCC Part 15.209 field strength limit;	Appendix H	Pass
AC Power Line Conducted Emissions	15.207	FCC Part 15.207 conducted limit;	Appendix I	Pass



3 Description of the Equipment under Test (EUT)

3.1 General Description

HUAWEI D2-6114, D2-6114, HW-03E is subscriber equipment in the LTE/UMTS/GSM system. The LTE frequency band is Band I, Band XIX and Band XXI, not included in this report. The HSUPA/HSDPA/UMTS frequency band is Band I, Band V, Band VI, and Band XIX. The GSM/GPRS/EDGE frequency band includes GSM850 and GSM900 and DCS1800 and PCS1900. The Mobile Phone implements such functions as RF signal receiving/transmitting, LTE/UMTS/GSM protocol processing, voice, video, MMS service, GPS, AGPS, Felica and WIFI etc. Externally it provides micro SD card interface, earphone port (to provide voice service) and USIM card interface. It also provides Bluetooth module to synchronize data between a PC and the phone, or to use the built-in modem of the phone to access the Internet with a PC, or to exchange data with other Bluetooth devices.

NOTE: Only Bluetooth test data included in this report.

3.2 EUT Identity

NOTE: Unless otherwise noted in the report, the functional boards installed in the units shall be selected from the below list, but not means all the functional boards listed below shall be installed in one unit.

3.2.1 Board

Board		
Software	Hardware Version	Description
4.1..1301141	HL1U9701LM	Main board of Mobile Phone

3.2.2 Sub-Assembly

Sub-Assembly			
Sub-Assembly Name	Model	Manufacturer	Description
Rechargeable Li-ion	HB5R1HV	Huawei Technologies Co., Ltd.	Battery Model: HB5R1HV Rated capacity: 2150mAh Nominal Voltage:  +3.8V Charging Voltage:  +4.35V



3.3 Technical Description

Characteristics	Description	
TX/RX Operating Range	2400-2483.5 MHz band	$f_c = 2402 \text{ MHz} + N * 1 \text{ MHz}$, where: - f_c = "Operating Frequency" in MHz, - N = "Channel Number" with the range from 0 to 78.
	Carrier	Frequency Hopping Spread Spectrum (FHSS)
Modulation Type	Digital	GFSK, $\pi/4$ -DQPSK, 8DPSK
	Emission Designator	GFSK: 0M87GXD $\pi/4$ -DQPSK: 1M28GXD GFSK for BT 4.0: 1M10GXD
Bluetooth Power Class	Class 2,	

4 General Test Conditions / Configurations

4.1 EUT Configurations

4.1.1 General Configurations

Configuration	Description
Test Antenna Ports	Until otherwise specified, <ul style="list-style-type: none"> - All TX tests are performed at all TX antenna ports of the EUT, and - All RX tests are performed at all RX antenna ports of the EUT.
Multiple RF Sources	Other than the tested RF source of the EUT, other RF source(s) are disabled or shutdown during measurements.

4.1.2 Customized Configurations

# EUT Conf.	Signal Description	Operating Frequency
TM1_DH5_Hop	GFSK modulation, package type DH5, hopping on.	---
TM1_DH5_Ch0	GFSK modulation, package type DH5, hopping off.	Ch No. 0 / 2402 MHz
TM1_DH5_Ch39	GFSK modulation, package type DH5, hopping off.	Ch No. 39 / 2441 MHz
TM1_DH5_Ch78	GFSK modulation, package type DH5, hopping off.	Ch No. 78 / 2480 MHz
TM2_2DH5_Hop	$\pi/4$ -DQPSK modulation, package type 2DH5, hopping on.	---
TM2_2DH5_Ch0	$\pi/4$ -DQPSK modulation, package type 2DH5, hopping off.	Ch No. 0 / 2402 MHz
TM2_2DH5_Ch39	$\pi/4$ -DQPSK modulation, package type 2DH5, hopping off.	Ch No. 39 / 2441 MHz
TM2_2DH5_Ch78	$\pi/4$ -DQPSK modulation, package type 2DH5, hopping off.	Ch No. 78 / 2480 MHz
TM3_3DH5_Hop	8DPSK modulation, package type 3DH5, hopping on.	---
TM3_3DH5_Ch0	8DPSK modulation, package type 3DH5, hopping off.	Ch No. 0 / 2402 MHz
TM3_3DH5_Ch39	8DPSK modulation, package type 3DH5, hopping off.	Ch No. 39 / 2441 MHz
TM3_3DH5_Ch78	8DPSK modulation, package type 3DH5, hopping off.	Ch No. 78 / 2480 MHz
TM4_DH5_Hop	GFSK for BT 4.0 modulation, package type DH5, hopping on.	---
TM4_DH5_Ch0	GFSK for BT 4.0 modulation, package type DH5, hopping off.	Ch No. 0 / 2402 MHz
TM4_DH5_Ch19	GFSK for BT 4.0 modulation, package type DH5, hopping off.	Ch No. 19 / 2440 MHz
TM4_DH5_Ch39	GFSK for BT 4.0 modulation, package type DH5, hopping off.	Ch No. 39 / 2480 MHz



4.2 Test Environments

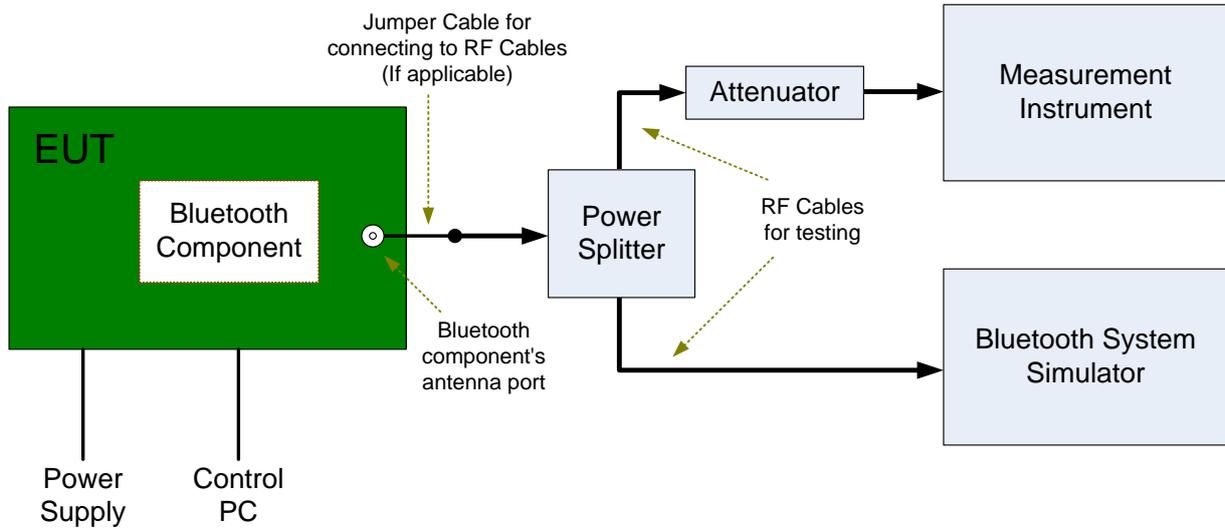
NOTE: The values used in the test report may be stringent than the declared.

Environment Parameter	Selected Values During Tests		
	Temperature	Voltage	Relative Humidity
NTNV	Ambient	3.8 VDC	Ambient

4.3 Test Setups

4.3.1 Test Setup 1

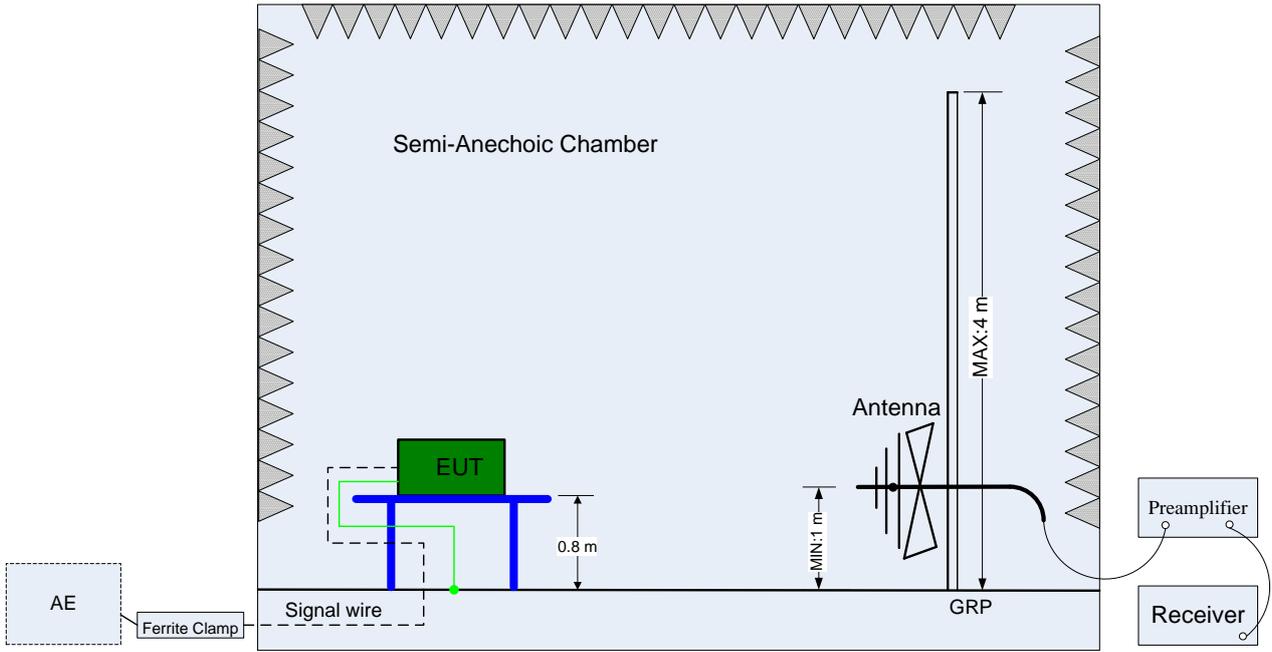
The Bluetooth component's antenna ports(s) of the EUT are connected to the measurement instrument per an appropriate attenuator. The EUT is controlled by Bluetooth System Simulator and/or PC/software to emit the specified signals for the purpose of measurements.



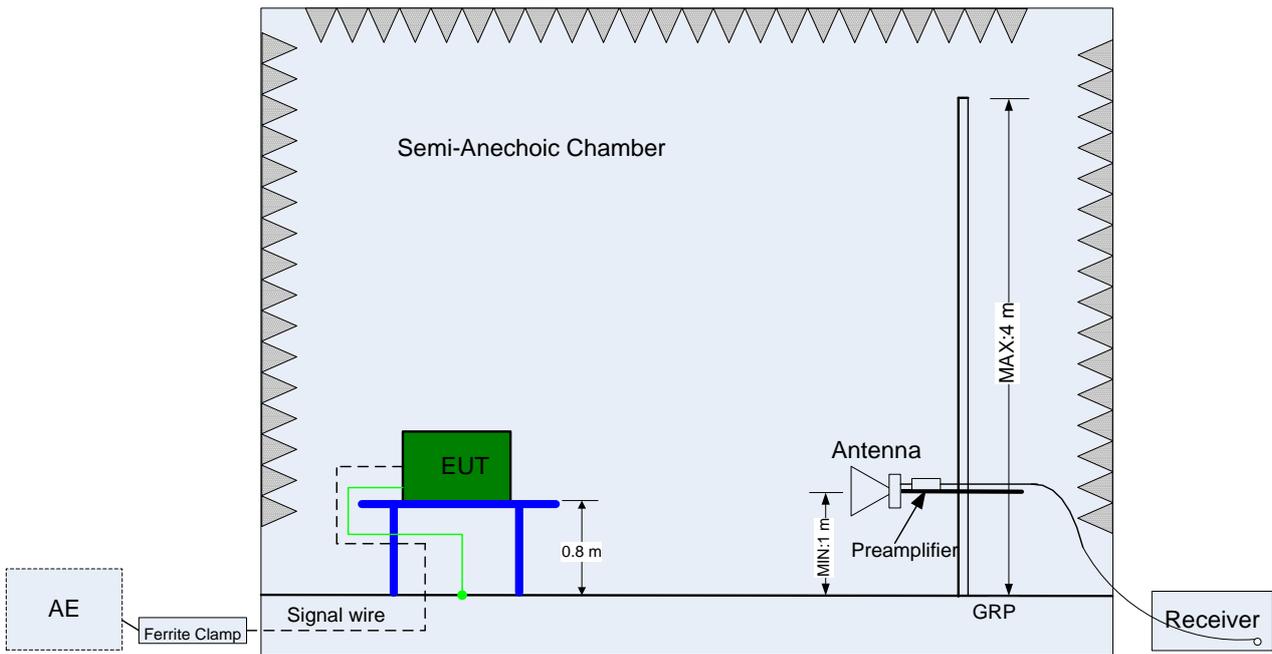
4.3.2 Test Setup 2

The test site semi-anechoic chamber has met the requirement of NSA tolerance 4 dB according to the standards: ANSI C63.4. The test distance is 3m. The setup is according to ANSI C63.4 and CAN/CSA-CEI/IEC CISPR 22.

The maximal emission value is acquired by adjusting the antenna height, polarisation and turntable azimuth. Normally, the height range of antenna is 1 m to 4 m, the azimuth range of turntable is 0° to 360°, and the receive antenna has two polarizations Vertical (V) and Horizontal (H).



(Below 1 GHz)

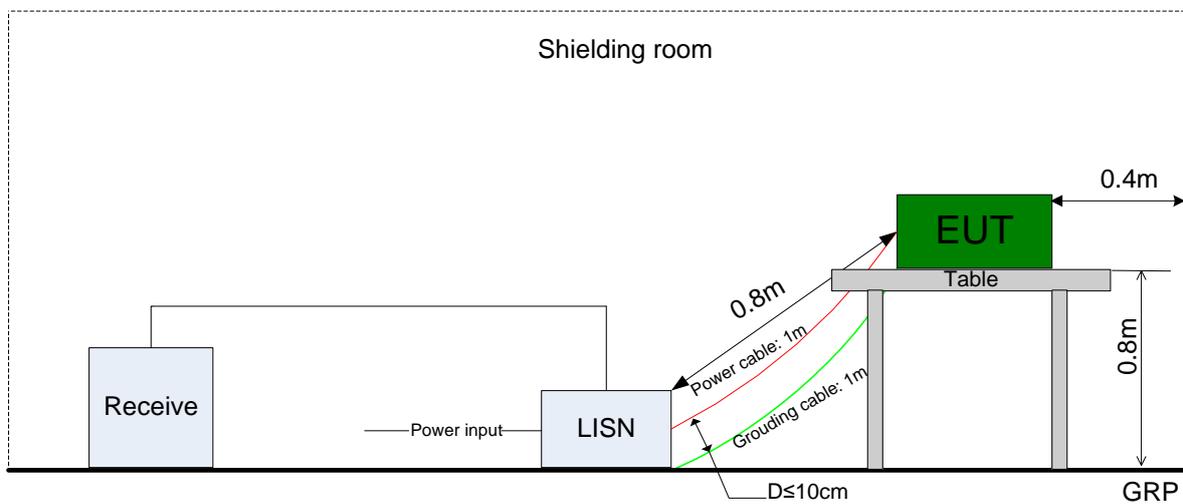


(Above 1 GHz)

4.3.3 Test Setup 3

The mains cable of the EUT (maybe per AC/DC Adapter) must be connected to LISN. The LISN shall be placed 0.8 m from the boundary of EUT and bonded to a ground reference plane for LISN mounted on top of the ground reference plane. This distance is between the closest points of the LISN and the EUT. All other units of the EUT and associated equipment shall be at least 0.8m from the LISN.

Ground connections, where required for safety purposes, shall be connected to the reference ground point of the LISN and, where not otherwise provided or specified by the manufacturer, shall be of same length as the mains cable and run parallel to the mains connection at a separation distance of not more than 0.1 m.



4.4 Test Conditions

Test Case	Test Conditions	
	Configuration	Description
20dB Emission Bandwidth (EBW)	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Ch0, TM1_DH5_Ch39, TM1_DH5_Ch78, TM2_2DH5_Ch0, TM2_2DH5_Ch39, TM2_2DH5_Ch78, TM3_3DH5_Ch0, TM3_3DH5_Ch39, TM3_3DH5_Ch78, TM4_DH5_Ch0, TM4_DH5_Ch19, TM4_DH5_Ch39.
Carrier Frequency Separation	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Hop, TM2_2DH5_Hop, TM3_3DH5_Hop,
Number of Hopping Channel	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Hop, TM2_2DH5_Hop, TM3_3DH5_Hop,
Time of Occupancy (Dwell Time)	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Ch39, TM2_2DH5_Ch39, TM3_3DH5_Ch39.
Maximum Peak Conducted Output Power	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Ch0, TM1_DH5_Ch39, TM1_DH5_Ch78, TM2_2DH5_Ch0, TM2_2DH5_Ch39, TM2_2DH5_Ch78, TM3_3DH5_Ch0, TM3_3DH5_Ch39, TM3_3DH5_Ch78, TM4_DH5_Ch0, TM4_DH5_Ch19, TM4_DH5_Ch39.
Band edge spurious emission	Meas. Method	DA 00-705
	Test Env.	NTNV
	Test Setup	Test Setup 1
	EUT Conf.	TM1_DH5_Ch0, TM1_DH5_Ch78, TM2_2DH5_Ch0, TM2_2DH5_Ch78, TM3_3DH5_Ch0, TM3_3DH5_Ch78.

Test Case	Test Conditions		
	Configuration	Description	
		TM4_DH5_Ch0, TM4_DH5_Ch39.	
Conducted RF Spurious Emission	Meas. Method	DA 00-705	
	Test Env.	NTNV	
	Test Setup	Test Setup 1	
	EUT Conf.	TM1_DH5_Ch0, TM1_DH5_Ch39, TM1_DH5_Ch78, TM2_2DH5_Ch0, TM2_2DH5_Ch39, TM2_2DH5_Ch78, TM3_3DH5_Ch0, TM3_3DH5_Ch39, TM3_3DH5_Ch78. TM4_DH5_Ch0, TM4_DH5_Ch19, TM4_DH5_Ch39.	
Radiated Emissions in the Restricted Bands	Meas. Method	DA 00-705, C63.4, C63.10. (1) 30 MHz to 1 GHz: Pre: RBW = 100 kHz; VBW = 300 kHz; Det. = Peak. Final: RBW = 120 kHz; Det. = CISPR Quasi-Peak. (2) 1 GHz to 26.5 GHz: Average: RBW = 1 MHz; VBW = 10 Hz; Det. = Peak; Sweep-time = Auto; Trace = Single. Peak: RBW = 1 MHz; VBW = 3 MHz; Det. = Peak; Sweep-time = Auto; Trace ≥ Max Hold * 100.	
	Test Env.	NTNV	
	Test Setup	Test Setup 2	
	EUT Conf.	30 MHz -1 GHz	TM1_DH5_Ch0 (Worst Conf.).
		1-3 GHz	TM1_DH5_Ch0, TM1_DH5_Ch39, TM1_DH5_Ch78, TM2_2DH5_Ch0, TM2_2DH5_Ch39, TM2_2DH5_Ch78, TM3_3DH5_Ch0, TM3_3DH5_Ch39, TM3_3DH5_Ch78. TM4_DH5_Ch0, TM4_DH5_Ch19, TM4_DH5_Ch39.
		3-18 GHz	TM1_DH5_Ch0 (Worse Conf.), TM1_DH5_Ch39 (Worse Conf.), TM1_DH5_Ch78 (Worse Conf.). TM4_DH5_Ch19 (Worse Conf.),
		18-26.5 GHz	TM1_DH5_Ch0 (Worst Conf.).
	AC Power Line Conducted Emissions	Meas. Method	AC mains conducted. Pre: RBW = 10 kHz; Det. = Peak. Final: RBW = 9 kHz; Det. = CISPR Quasi-Peak & Average.
Test Env.		NTNV	
Test Setup		Test Setup 3	
EUT Conf.		TM1_DH5_Ch39.	



5 Main Test Instruments

NOTE: Unless otherwise specified, the calibration intervals for test instruments were Annual (per year). The other intervals, if applicable, are marked with (##y), which denotes ## years calibration interval.

Equipment Name	Manufacturer	Model	Serial Number	Cal Date	Cal. Due
Power supply	KEITHLEY	2303	1288003	2012-11-19	2014-11-18
Wireless Communication Test set	Agilent	N4010A	MY49081592	2012-11-09	2013-11-08
Spectrum Analyzer	Agilent	E4440A	MY48250119	2012-08-20	2013-08-19
Signal Analyzer	R&S	FSQ31	200021	2012-11-09	2013-11-08
Spectrum Analyzer	Agilent	N9030A	MY49431698	2012-11-09	2013-11-08
Temperature Chamber	WEISS	WKL64	56246002940010	2013-01-29	2014-01-28
Signal generator	Agilent	E8257D	MY49281095	2012-09-14	2013-09-13
Test receiver	R&S	ESU26	100150	2012-05-28	2013-05-27
Spectrum analyzer	R&S	FSU3	200474	2013-01-29	2014-01-28
Spectrum analyzer	R&S	FSU43	100144	2013-01-29	2014-01-28
Double-Ridged Waveguide Horn Antenna (1G~18GHz)	R&S	HF907	100304	2013-02-02	2014-02-01
Double-Ridged Waveguide Horn Antenna (1G~18GHz)	R&S	HF907	100391	2011-10-12	2013-10-11
Trilog Broadband Antenna (30M~3GHz)	SCHWARZBE CK	VULB 9163	9163-521	2011-12-09	2013-12-08
Pyramidal Horn Antenna(26GHz-40GH z)	ETS-Lindgren	3160-10	00123940	2011-02-28	2013-02-27
Pyramidal Horn Antenna(18GHz-26.5G Hz)	ETS-Lindgren	3160-09	00125912	2011-02-28	2013-02-27

END